# PC910L0NSZ

\* VDE (VDE0884) approved type is also available us an option

#### ■ Features

1. Ultra-high speed response

 $(t_{PHL}, t_{PLH}: TYP. 50ns at R_L=350\Omega)$ 

2. Isolation voltage between input and output (V<sub>iso (rms)</sub>: 5.0kV)

3. Low input current drive (I<sub>FHL</sub>: MAX. 5mA)

4. Instantaneous common mode rejection voltage (CM<sub>H</sub>:TYP. 20kV/µs)

5. TTL and LSTTL compatible output

6. Recognized by UL, file No. E64380 (model No. PC910L)

#### ■ Applications

1. High speed interfaces for computer peripherals

2. Programmable controllers

3. Inverters

(T	=25	°C)

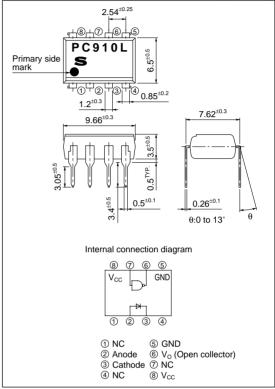
Parameter		Symbol	Rating	Unit
	*1 Forward current	$I_F$	20	mA
Input	Reverse voltage	V <sub>R</sub>	5	V
Power dissipation		P	40	mW
	Supply voltage	V <sub>CC</sub>	7	V
nt	*2 Enable voltage	V <sub>E</sub>	5.5	V
Output	High level output voltage	V <sub>OH</sub>	7	V
	Low level output current	$I_{OL}$	50	mA
	Collector power dissipation	P <sub>C</sub>	85	mW
*3 Isolation voltage		V <sub>iso (rms)</sub>	5.0	kV
Operating temperature		$T_{opr}$	-40 to +85	°C
Storage temperature		T <sub>stg</sub>	-55 to +125	°C
*4 Soldering temperature		T <sub>sol</sub>	270	°C

<sup>\*1</sup> T<sub>a</sub>=T<sub>opr</sub>

# Ultra-High Speed Response \*OPIC Photocoupler

### **■** Outline Dimensions

(Unit: mm)



<sup>\* &</sup>quot;OPIC"(Optical IC) is a trademark of the SHARP Corporation. An OPIC consists of a light-detecting element and signal-processing circuit integrated onto a single chip.

<sup>\*2</sup> Shall not exceed 500mV from supply voltage (V<sub>CC</sub>)

<sup>\*3 40</sup> to 60%RH, AC for 1minute

<sup>\*4</sup> For 10s

■ Elect	ro-	optical Characteristics	3	(Unspecified $T_a=-40$ to $+85^{\circ}$ C, A	ll typical	values at	T <sub>a</sub> =25°C,	$V_{CC}=5V$
		Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Forward voltage		ward voltage	V <sub>F</sub>	$T_a=25$ °C, $I_F=10$ mA	_	1.6	1.9	V
Input	Re	verse current	$I_R$	T <sub>a</sub> =25°C, V <sub>R</sub> =5V	-	_	10	μΑ
	Tei	Terminal capacitance		T <sub>a</sub> =25°C, V=0, f=1kHz	_	60	150	pF
Output	High level output voltage		$I_{OH}$	$V_{CC}=V_{O}=5.5V, V_{E}=2.0V, I_{F}=250\mu A$	_	0.02	100	μΑ
	Low level output voltage		V <sub>OL</sub>	$V_{CC}=V_{O}=5.5V, V_{E}=2.0V, I_{F}=5mA, I_{OL}=13mA$	_	0.4	0.6	V
	High level enable current		$I_{EH}$	V <sub>CC</sub> =5.5V, V <sub>E</sub> =2.0V	_	-0.5	-1.6	mA
	Low level enable current		$I_{EL}$	$V_{CC}=5.5V, V_{E}=0.5V$	_	-0.7	-1.6	mA
	11:	TT 1 1 1 1		$V_{CC}=5.5V, I_F=0, V_E=2V$	_	5	10	mA
	Пі	gh level supply current	$I_{CCH}$	$V_{CC}=5.5V, I_F=0, V_E=0.5V$	_	5	_	mA
	T		I <sub>CCL</sub>	$V_{CC}=5.5V, I_{F}=10mA, V_{E}=2V$	_	7	13	mA
	LO	Low level supply current		$V_{CC}$ =5.5V, $I_F$ =10mA, $V_E$ =0.5V	_	5.5	_	mA
	"High→Low" threshold input current		$I_{FHL}$	$V_{CC}$ =5V, $V_{E}$ =2.0V, $V_{O}$ =0.8V, $R_{L}$ =350 $\Omega$	_	2.5	5	mA
	Isolation resistance		R <sub>ISO</sub>	T <sub>a</sub> =25°C, DC=500V, 40 to 60%RH	5×10 <sup>10</sup>	1011	_	Ω
	Floating capacitance		$C_{\rm f}$	T <sub>a</sub> =25°C, V=0, f=1MHz	-	0.6	5	pF
		"High-Low" propagation time		Fig. 1	25	48	75	ns
	"Low-High" propagation time		t <sub>PLH</sub>	$T_a=25^{\circ}\text{C}, V_{CC}=5\text{V}, R_L=350\Omega,$	25	50	75	ns
	le	ଥ Rise time		$C_L=15 \text{pF}, I_F=7.5 \text{mA}$	_	10	_	ns
	e tir	Fall time	$t_{\rm f}$	OL 18p1, II / ISBN 1	_	20	_	ns
Transfer	*7 Distortion of pulse width		$\Delta t_{\mathrm{w}}$		_	_	35	ns
charac- teristics	Rise time  Fall time  *7 Distortion of pulse width  "High—Low" enable propagation delay time		t <sub>EHL</sub>	$T_a$ =25°C, $V_{CC}$ =5V, $R_1$ =350Ω, $C_1$ =15pF,	_	15	_	ns
	"Low→High" enable propagation delay time	e e	t <sub>ELH</sub>	$I_F=7.5$ mA, $V_{EH}=3$ V, $V_{EL}=0.5$ V	_	10	_	ns
	CMR	Instantaneous common mode rejection voltage "Output : High level"	СМн	$\begin{array}{c} \text{Fig.3} \\ T_a \!\!=\!\! 25^{\circ}\text{C},  V_{\text{CC}} \!\!=\!\! 5\text{V},  V_{\text{CM}} \!\!=\!\! 1\text{kV}_{\text{(P-P)}}, \\ R_L \!\!=\!\! 350\Omega,  I_F \!\!=\!\! 0,  V_{O(\text{Min})} \!\!=\!\! 2\text{V} \end{array}$	10	20	_	kV/μs
	Instantaneous common		$CM_L$	$\begin{array}{c} Fig.3 \\ T_a \!\!=\!\! 25^\circ C, V_{CC} \!\!=\!\! 5V, V_{CM} \!\!=\!\! 1kV_{(P\!-P)}, \\ R_L \!\!=\!\! 350\Omega, I_F \!\!=\!\! 5mA, V_{O(Max)} \!\!=\!\! 0.8V \end{array}$	-10	-20	_	kV/μs

<sup>\*6</sup> It shall connect a by-pass capacitor of  $0.01\mu F$  or more between  $V_{CC}$  (Pin \$) and GND (Pin \$) near the device, when it measures the transfer characteristics and the output side characteristics

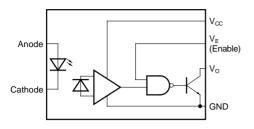
## **■** Recommended Operating Conditions

Parameter	Symbol	MIN.	MAX.	Unit
Low level input current	$I_{FL}$	0	250	μΑ
High level input current	$I_{FH}$	8	15	mA
High level enable voltage	V <sub>EH</sub>	2.0	$V_{CC}$	V
Low level enable voltage	V <sub>EL</sub>	0	0.8	V
Supply voltage	V <sub>CC</sub>	4.5	5.5	V
Fanout (TTL load)	N	_	8	_
Operating temperature	Topr	-40	85	°C

<sup>1.</sup> When the enable input is in high level state, external pull-up resistor is unnecessary

<sup>\*7</sup> Distortion of pulse width  $\Delta t_w\!\!=\!\mid t_{PHL}\!\!-\!t_{PLH}\mid$ 

### ■ Circuit Block Diagram

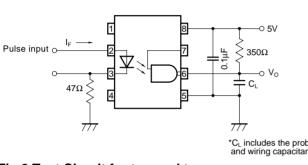


#### **■** Truth Table

Input	Enable	Output
Н	Н	L
L	Н	Н
Н	L	Н
L	L	Н

L:Logic (0) H:Logic (1)

Fig.1 Test Circuit for  $t_{\text{PHL}},\,t_{\text{PLH}},\,t_{\text{r}}$  and  $t_{\text{f}}$ 



\*C<sub>L</sub> includes the probe and wiring capacitance.

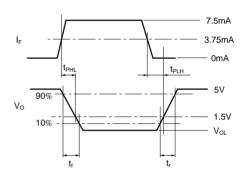
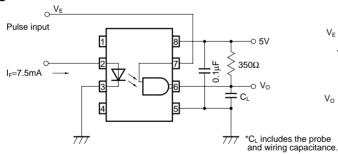


Fig.2 Test Circuit for t<sub>EHL</sub> and t<sub>ELH</sub>

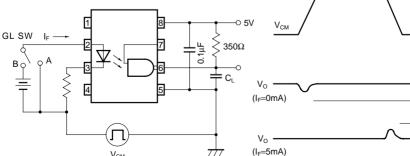


3V 1.5V 0.5V t<sub>EHL</sub>  $t_{\mathsf{ELH}}$ 5V 1.5V  $V_{\text{OL}} \\$ 

1kV

 $V_{OL}$ 

Fig.3 Test Circuit for CM<sub>H</sub> and CM<sub>L</sub>



When the switch for infrared light emitting  $V_O(MIN.)$  diode sets to A

 $V_{O}(MAX.)$  When the switch for infrared light emitting diode sets to B

\*C<sub>L</sub> includes the probe and wiring capacitance.

Fig.4 Forward Current vs. Ambient Temperature

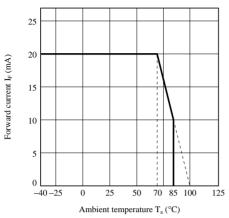


Fig.6 Forward Current vs. Forward Voltage

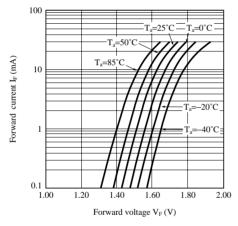


Fig.8 Low Level Output Voltage vs. Ambient Temperature

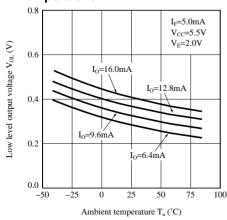


Fig.5 Collector Power Dissipation vs. Ambient Temperature

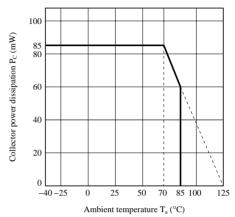


Fig.7 High Level Output Current vs. Ambient Temperature

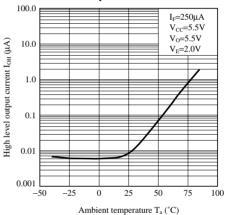
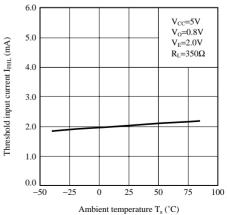


Fig.9 Threshold Input Current vs. Ambient Temperature



PC910L0NSZ

Fig.10 Output Voltage vs. Forward Current

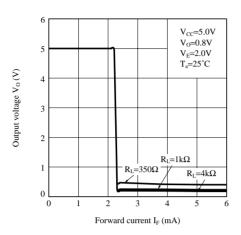


Fig.12 Propagation Delay Time vs. Ambient Temperature

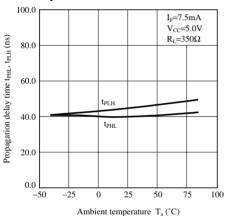
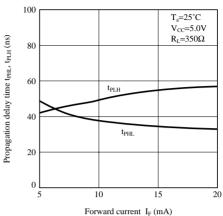


Fig.11 Propagation Delay Time vs. Forward Current



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